Annex A: System Check
Tested Model : X1302
Report Number: **WSCT-ANAB-R&E250800070A-SAR**

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Measurement Report for Device, , , UID 0 -, Channel 0 (750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	750.000, 0	9.16	0.885	43.9

Hardware Setup

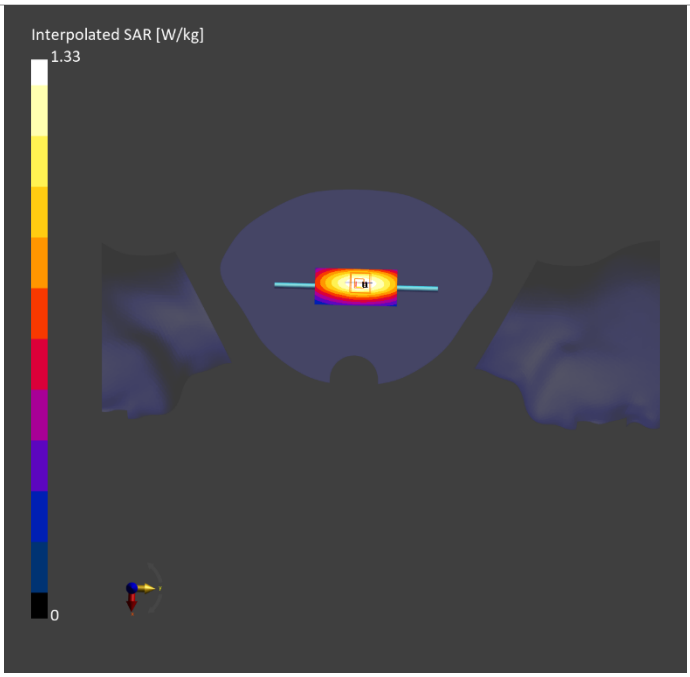
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-08-30	2025-08-30
psSAR1g [W/kg]	0.853	0.858
psSAR10g [W/kg]	0.573	0.570
Power Drift [dB]	0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.4
Dist 3dB Peak [mm]		22.1



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Measurement Report for Device, , , UID 0 -, Channel 0 (835.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	835.000, 0	8.89	0.914	41.6

Hardware Setup

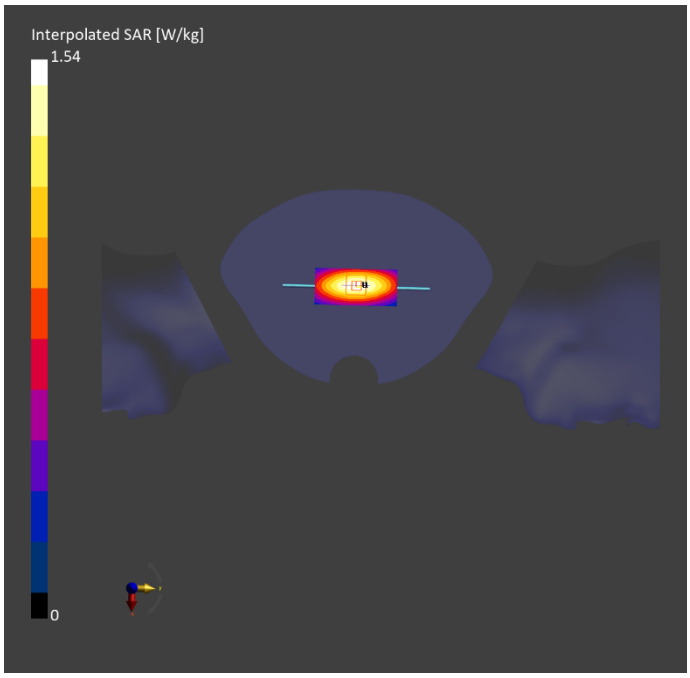
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-02	2025-09-02
psSAR1g [W/kg]	0.993	0.994
psSAR10g [W/kg]	0.653	0.655
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		86.2
Dist 3dB Peak [mm]		16.4



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Measurement Report for Device, , , UID 0 -, Channel 0 (1750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	1750.000, 0	7.6	1.34	41.9

Hardware Setup

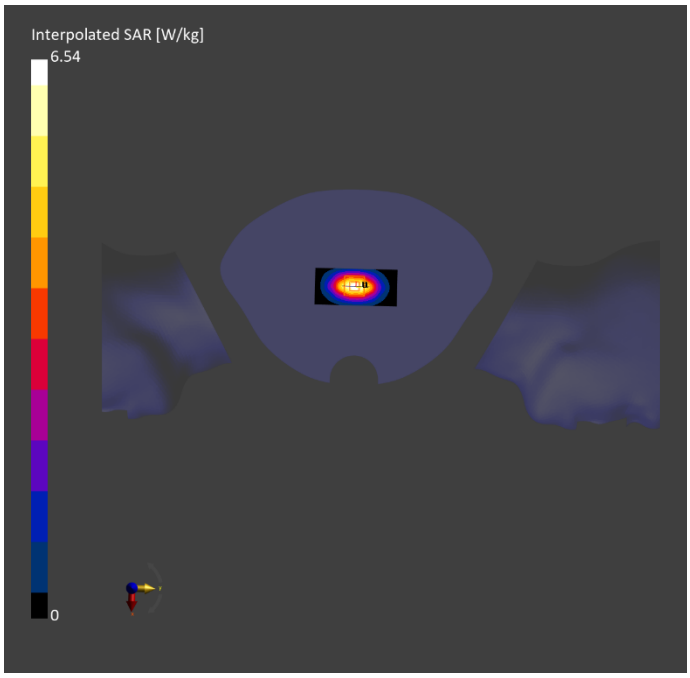
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-04	2025-09-04
psSAR1g [W/kg]	3.62	3.62
psSAR10g [W/kg]	1.92	1.95
Power Drift [dB]	0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.2
Dist 3dB Peak [mm]		10.8



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Measurement Report for Device, , , UID 0 -, Channel 0 (1900.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	1900.000, 0	7.33	1.44	41.7

Hardware Setup

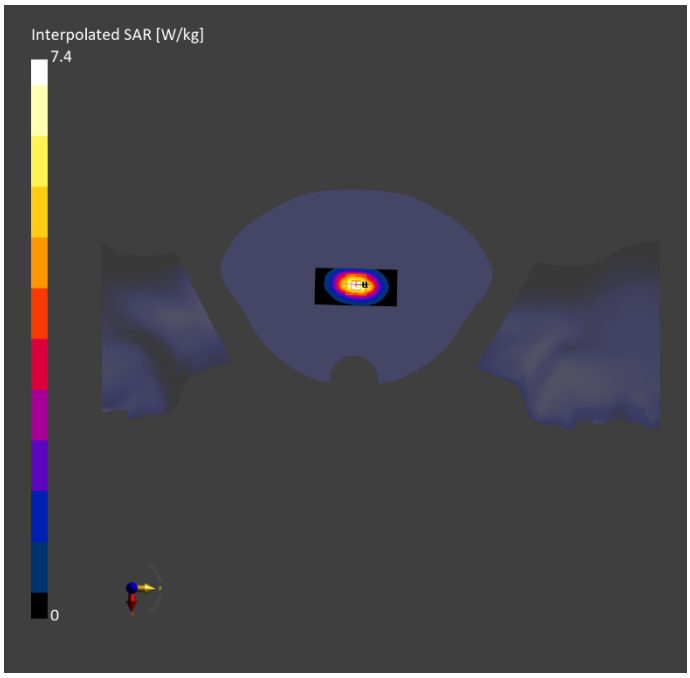
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 90.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-06	2025-09-06
psSAR1g [W/kg]	4.01	4.04
psSAR10g [W/kg]	2.10	2.11
Power Drift [dB]	-0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.0
Dist 3dB Peak [mm]		9.6



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Measurement Report for Device, , , UID 0 -, Channel 0 (2550.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	2550.000, 0	6.94	1.90	40.8

Hardware Setup

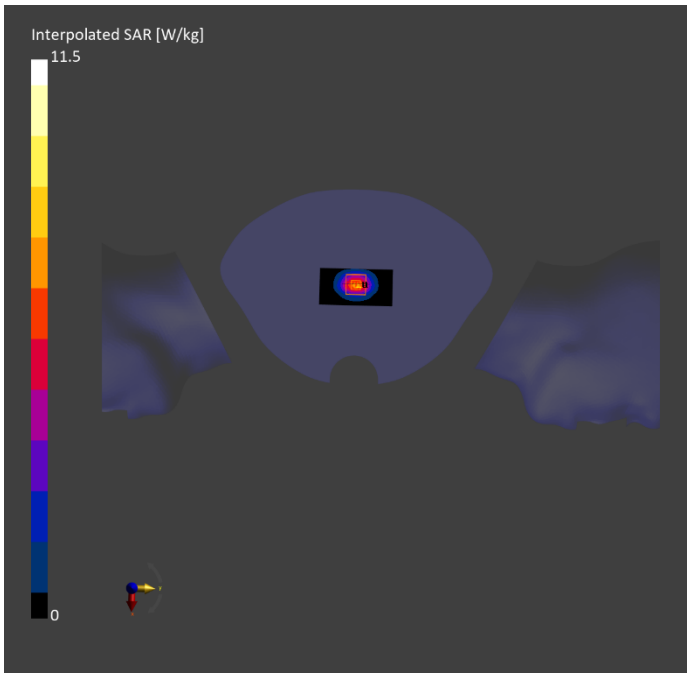
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-10	2025-09-10
psSAR1g [W/kg]	5.48	5.58
psSAR10g [W/kg]	2.53	2.56
Power Drift [dB]	0.00	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.5
Dist 3dB Peak [mm]		9.0



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Measurement Report for Device, , , UID 0 -, Channel 0 (5200.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5200.000, 0	5.34	4.54	36.3

Hardware Setup

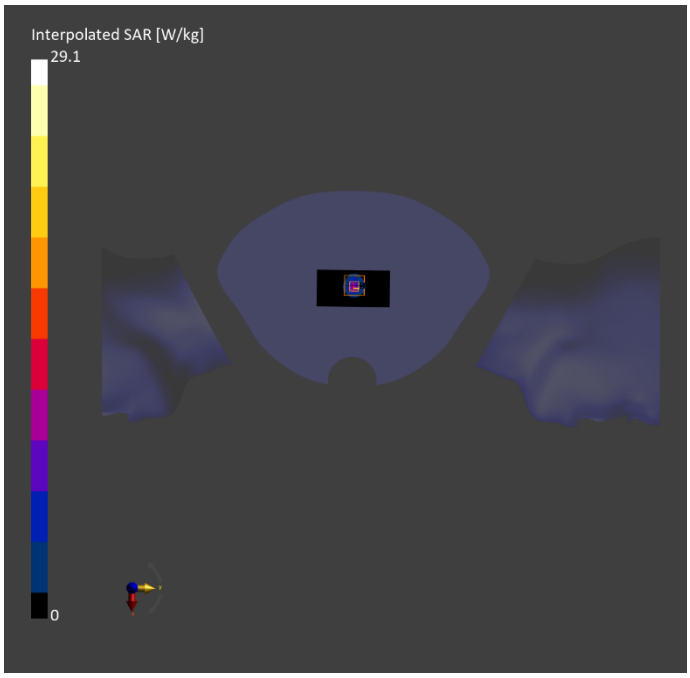
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-15	2025-09-15
psSAR1g [W/kg]	6.41	7.17
psSAR10g [W/kg]	1.91	2.07
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		62.3
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5300.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5300.000, 0	5.28	4.65	36.2

Hardware Setup

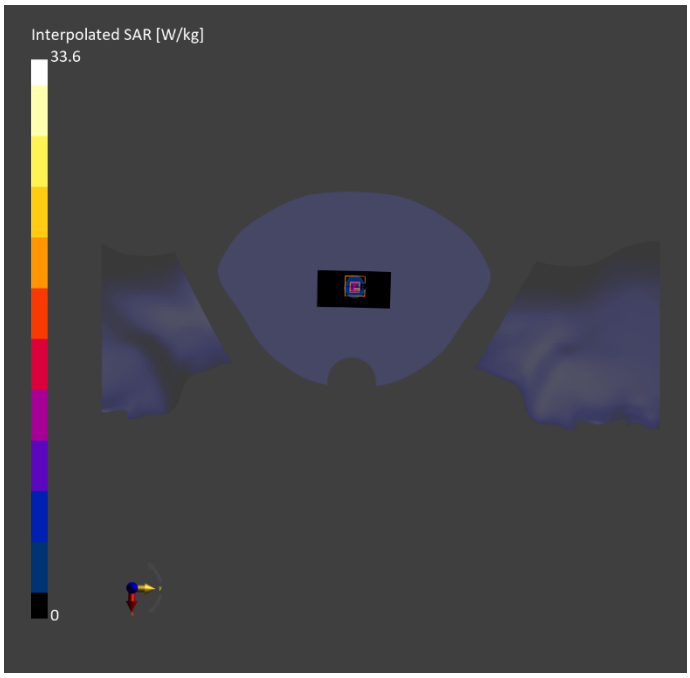
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-15	2025-09-15
psSAR1g [W/kg]	7.15	8.08
psSAR10g [W/kg]	2.09	2.31
Power Drift [dB]	0.01	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.4
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5500.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5500.000, 0	4.87	4.88	35.8

Hardware Setup

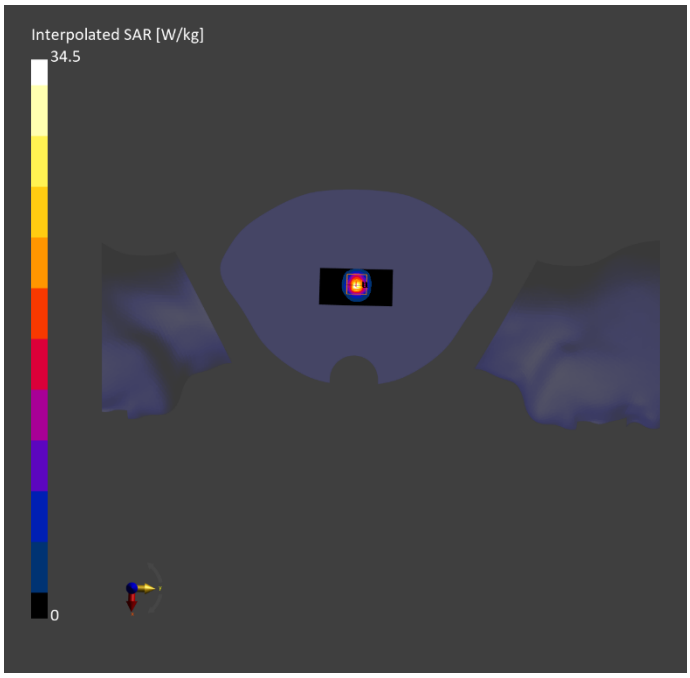
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-16	2025-09-16
psSAR1g [W/kg]	6.98	7.90
psSAR10g [W/kg]	2.03	2.25
Power Drift [dB]	0.03	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		59.5
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5600.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5600.000, 0	4.87	5.00	35.6

Hardware Setup

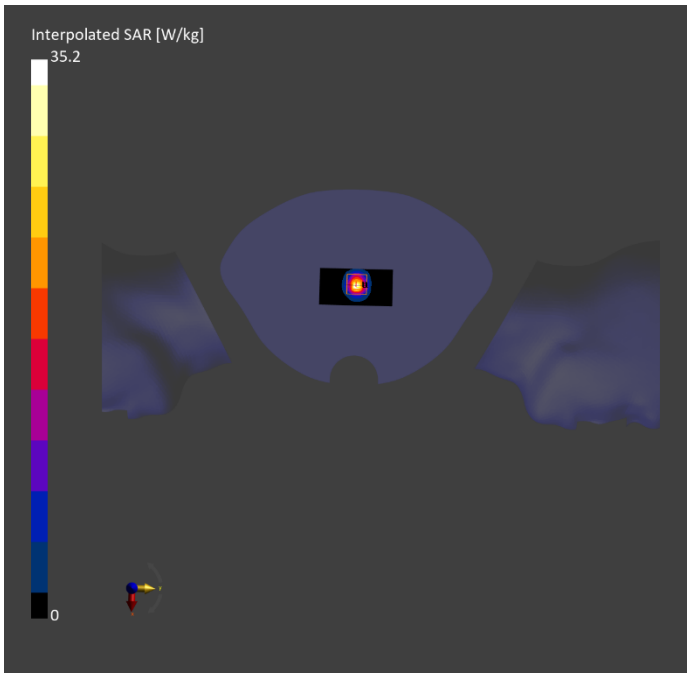
Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-16	2025-09-16
psSAR1g [W/kg]	7.00	7.87
psSAR10g [W/kg]	2.04	2.24
Power Drift [dB]	0.02	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.4
Dist 3dB Peak [mm]		7.2



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Measurement Report for Device, , , UID 0 -, Channel 0 (5800.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	50.0 x 10.0 x 8.0		Dipole

Exposure Conditions

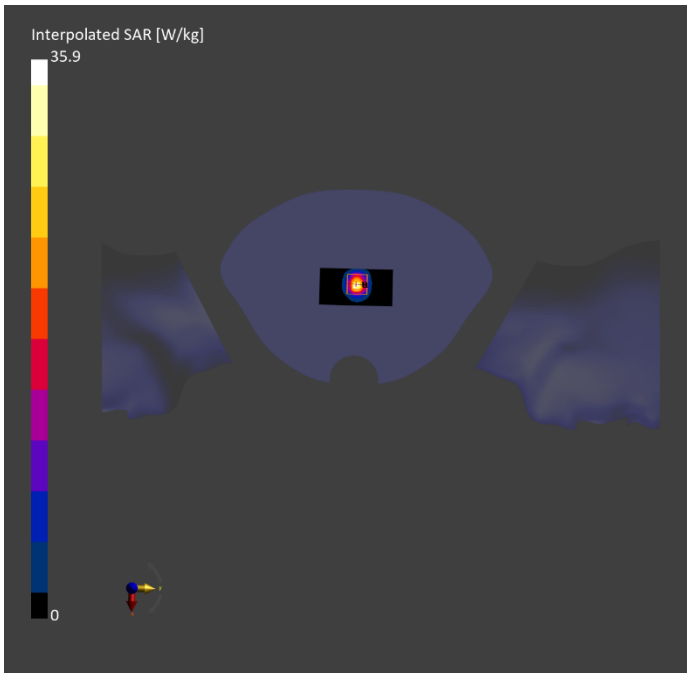
Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat, Head Simulating Liquid	,		CW, 0--	5800.000, 0	4.84	5.23	35.3

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx, --	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	40.0 x 80.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

Measurement Results

	Area Scan	Zoom Scan
Date	2025-09-17	2025-09-17
psSAR1g [W/kg]	6.76	7.76
psSAR10g [W/kg]	2.00	2.20
Power Drift [dB]	0.01	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		56.9
Dist 3dB Peak [mm]		7.6